

Capacitors, E. Benabe, K. Skowronski, T. Weller, H. Gordon, P. Warder

4:50 pm Adjourn

Friday, December 4, 1998

8:30 am Session E: Measurement Standards

E1 Standards for Broadband Wireless Access Systems, R. Marks

E2 Design of Components for a 7-16 Precision Calibration Kit Using the High Frequency Structure Simulator, B. Szendrenyi

E3 Ground-Signal Standards for RF Probing, R. Chavez

9:45 am Break (Exhibits Open)

10:30 am Session F: Characterization Techniques for Wireless Systems

F1 Measuring and Modeling Package Interconnects Using Vector Network Analyzers and Time Domain Transforms, J. Dunsmore

F2 NIST Passive Inter-Modulation Measurement Comparison for Wireless Base-Station Equipment, J. Jargon, D. DeGroot

F3 Integrating System Level Design and Instrumentation for Communication Development, F. Palmer

F4 Power Amplifier Design, A. Howard

12:10 pm Lunch

1:30 pm Tour of Hewlett Packard's Santa Rosa Facility (Bus leaves at hotel lobby)

HP EEsof (High-frequency CAD tools)
Microwave Technology Center (GaAs fab and integrated circuits)
Microwave Test Accessories (Standards lab)
Santa Rosa Systems Division (RFIC, satellite, EMC, and aerospace and defense test systems)

4:00 pm Arrive back at conference hotel - conference adjourns